



## Description

### JMT P-channel Enhancement Mode Power MOSFET

#### Features

- $V_{DS} = -20V$ ,  $I_D = -55A$
- $R_{DS(ON)} < 8.3m\Omega$  @  $V_{GS} = -4.5V$
- $R_{DS(ON)} < 10.4m\Omega$  @  $V_{GS} = -2.5V$
- High Power and Current Handling Capability
- Lead Free Product is Acquired
- Surface Mount Package

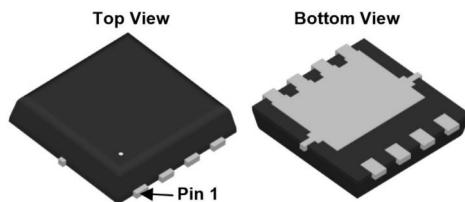
#### Application

- PWM Applications
- Load Switch

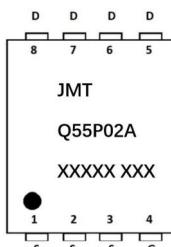


100% UIS TESTED!

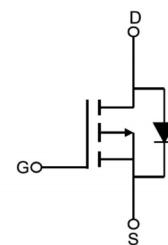
100%  $\Delta V_{ds}$  TESTED!



PDFN3x3-8L



Marking and pin Assignment



Schematic Diagram

## Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
JMTQ55P02A	JMTQ55P02A	TAPING	PDFN3x3-8L	13inch	5000	50000

## Absolute Maximum Ratings ( $T_C = 25^\circ C$ unless otherwise specified)

Symbol	Parameter		Max.	Units
$V_{DSS}$	Drain-Source Voltage		-20	V
$V_{GSS}$	Gate-Source Voltage		$\pm 12$	V
$I_D$	Continuous Drain Current	$T_C = 25^\circ C$	-55	A
		$T_C = 100^\circ C$	-35	
$I_{DM}$	Pulsed Drain Current <sup>note1</sup>		-220	A
$E_{AS}$	Single Pulsed Avalanche Energy <sup>note2</sup>		90	mJ
$P_D$	Power Dissipation	$T_C = 25^\circ C$	66	W
$R_{eJC}$	Thermal Resistance, Junction to Case		1.9	$^\circ C / W$
$T_J$ , $T_{STG}$	Operating and Storage Temperature Range		-55 to +150	$^\circ C$

**Electrical Characteristics** ( $T_J=25^\circ\text{C}$  unless otherwise specified)

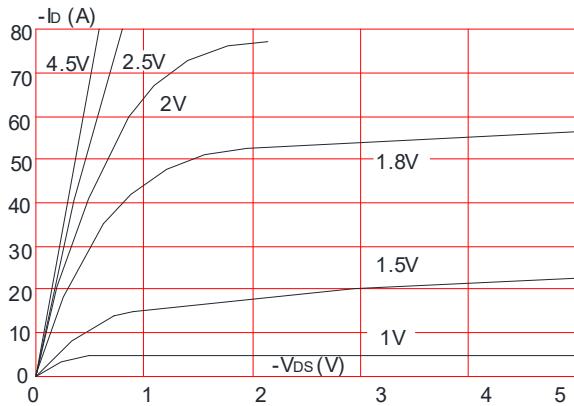
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristic</b>						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D = -250\mu\text{A}$	-20	-	-	V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS} = -20\text{V}$ , $V_{GS} = 0\text{V}$ ,	-	-	-1	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS} = 0\text{V}$ , $V_{GS} = \pm 12\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = -250\mu\text{A}$	-0.4	-0.65	-1.0	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS} = -4.5\text{V}$ , $I_D = -15\text{A}$	-	6.6	8.3	$\text{m}\Omega$
		$V_{GS} = -2.5\text{V}$ , $I_D = -12\text{A}$	-	8	10.4	
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = -10\text{V}$ , $V_{GS} = 0\text{V}$ , $f = 1.0\text{MHz}$	-	4770	-	pF
$C_{oss}$	Output Capacitance		-	570	-	pF
$C_{rss}$	Reverse Transfer Capacitance		-	502	-	pF
$Q_g$	Total Gate Charge	$V_{DS} = -10\text{V}$ , $I_D = -15\text{A}$ , $V_{GS} = -4.5\text{V}$	-	56	-	nC
$Q_{gs}$	Gate-Source Charge		-	8	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	16	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = -10\text{V}$ , $I_D = -13\text{A}$ , $R_{\text{GEN}} = 2.7\Omega$ , $V_{GS} = -10\text{V}$	-	11	-	ns
$t_r$	Turn-on Rise Time		-	110	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	157	-	ns
$t_f$	Turn-off Fall Time		-	160	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_s$	Maximum Continuous Drain to Source Diode Forward Current	-	-	-55	-	A
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	-220	-	A
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}$ , $I_s = -30\text{A}$	-	-	-1.2	V
$trr$	Reverse Recovery Time	$T_J = 25^\circ\text{C}$ , $I_s = -15\text{A}$ , $di/dt = -100\text{A}/\mu\text{s}$	-	23	-	ns
$Qrr$	Reverse Recovery Charge		-	14	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

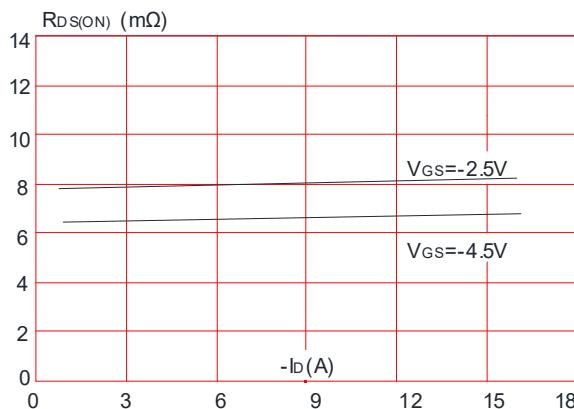
2. EAS condition:  $T_J = 25^\circ\text{C}$ ,  $V_{DD} = -10\text{V}$ ,  $V_G = -10\text{V}$ ,  $R_G = 25\Omega$ ,  $L = 0.5\text{mH}$ ,  $I_{AS} = -19\text{A}$ 3. Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 0.5\%$

## Typical Performance Characteristics

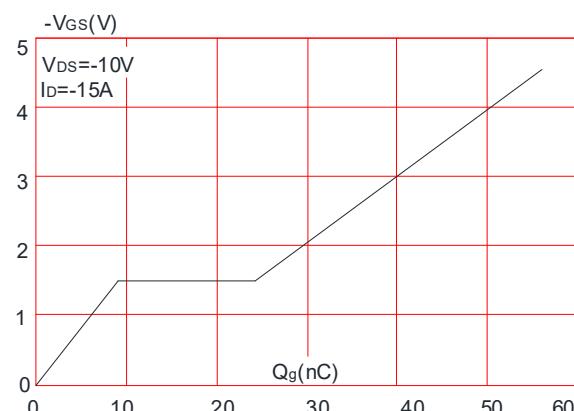
**Figure 1:** Output Characteristics



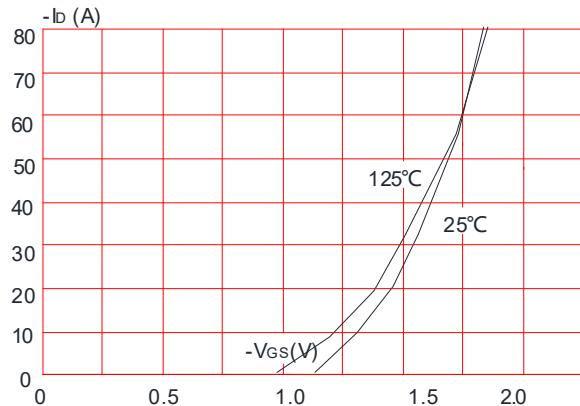
**Figure 3:** On-resistance vs. Drain Current



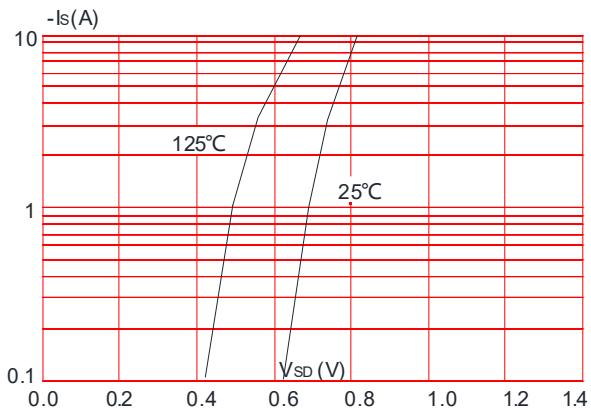
**Figure 5: Gate Charge Characteristics**



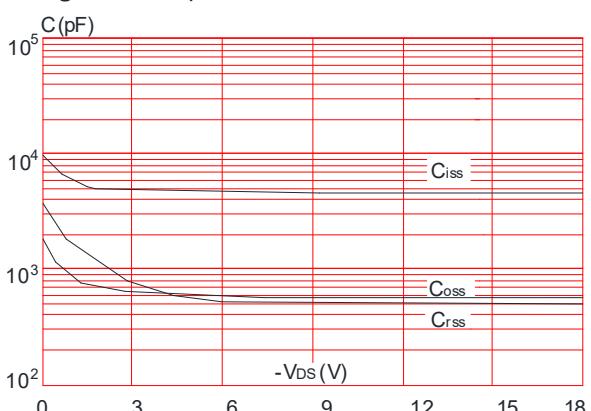
**Figure 2:** Typical Transfer Characteristics



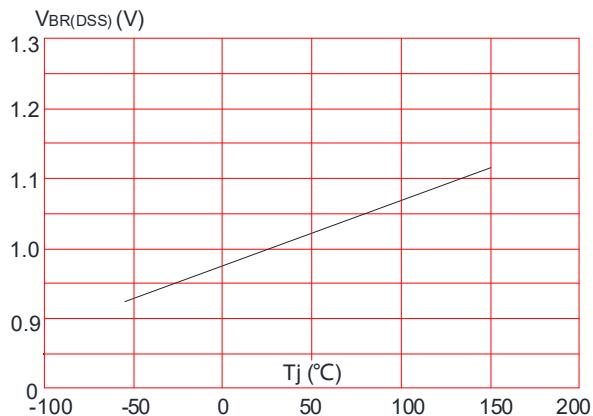
**Figure 4 : Body Diode Characteristics**



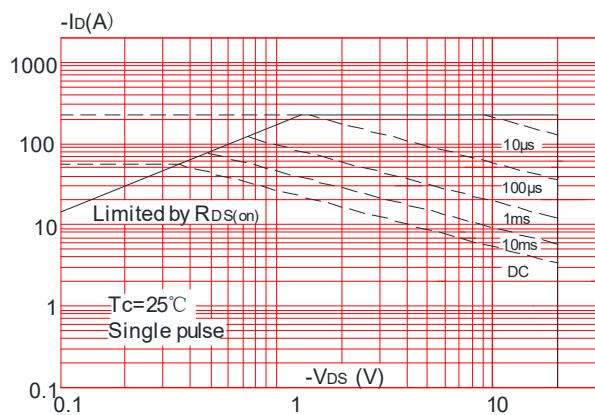
**Figure 6: Capacitance Characteristics**



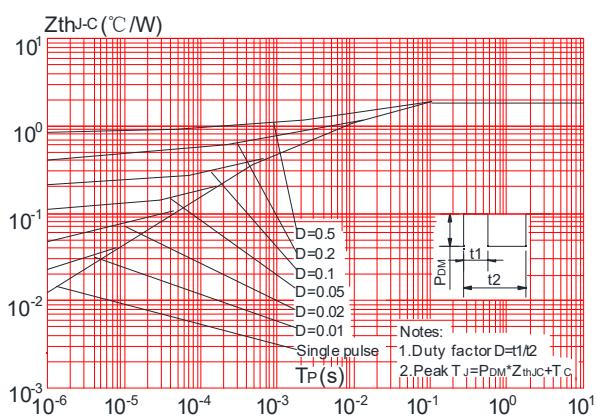
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



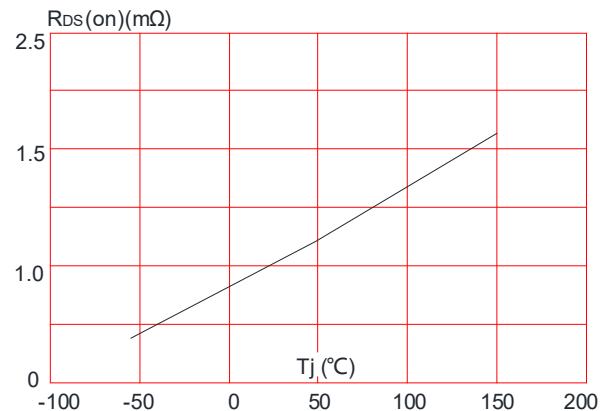
**Figure 9:** Maximum Safe Operating Area



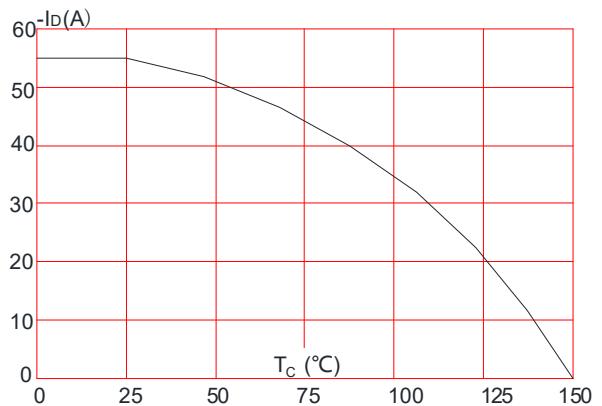
**Figure.11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



**Figure 8:** Normalized on Resistance vs. Junction Temperature

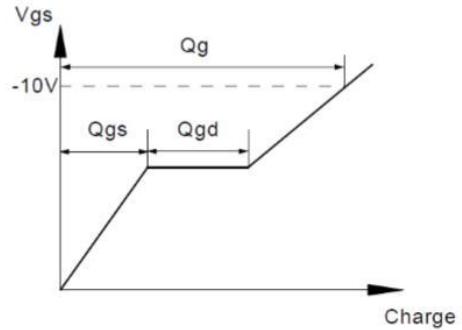
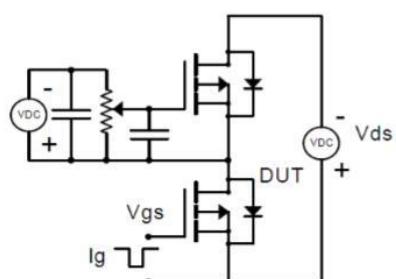


**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature

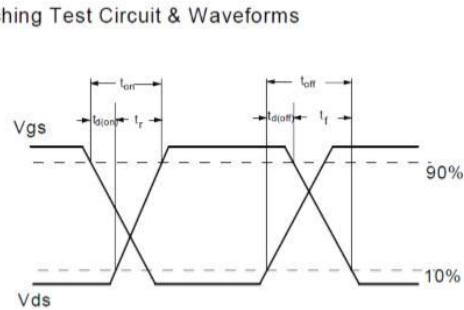
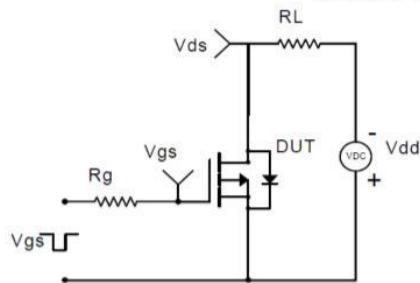


## Test Circuit

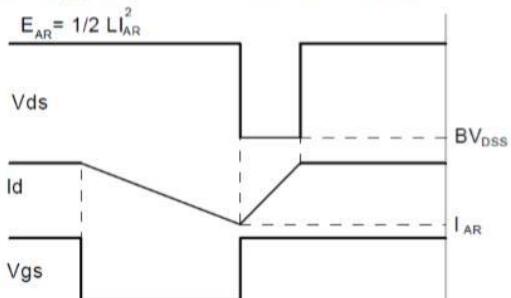
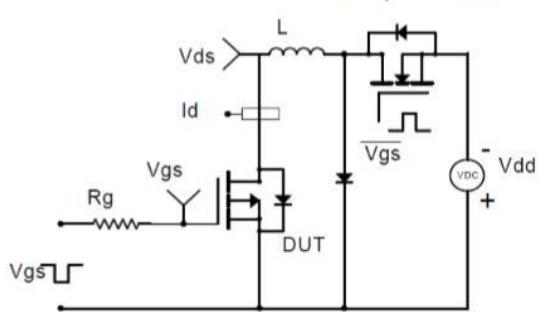
Gate Charge Test Circuit & Waveform



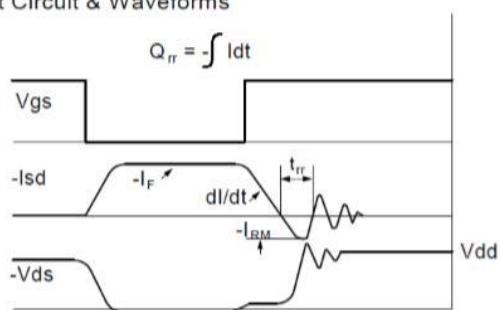
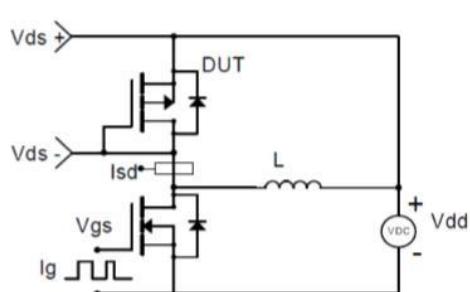
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

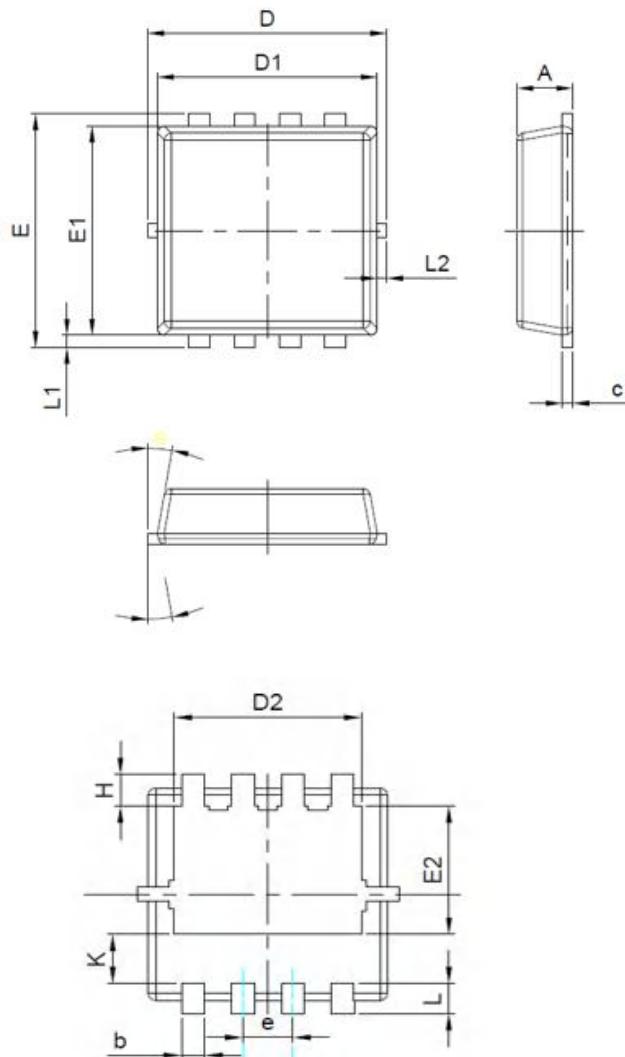


Diode Recovery Test Circuit & Waveforms





## Package Mechanical Data-PDFN3x3-8L



## COMMON DIMENSIONS

( UNITS OF MEASURE = MILLIMETER )

SYMBOL	MIN	NOM	MAX
A	0.70	0.80	0.90
b	0.25	0.30	0.39
c	0.14	0.15	0.25
D	3.20	3.30	3.40
D1	3.00	3.15	3.30
D2	2.35	2.45	2.55
e	0.65 BSC		
E	3.25	3.35	3.45
E1	2.85	3.00	3.15
E2	1.635	1.735	1.835
H	0.33	0.48	0.63
K	0.585	0.685	0.785
L	0.30	0.40	0.50
L1	0.05	0.15	0.25
L2	-	-	0.15
θ	8°	10°	12°

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